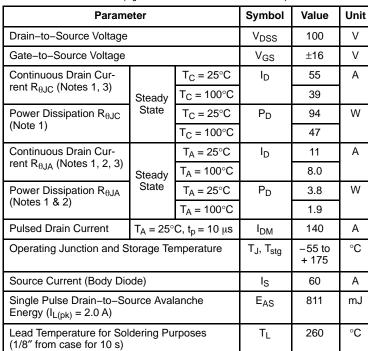
## **Power MOSFET** 100 V, 13 mΩ, 55 A, Single N–Channel

#### Features

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS6B14NLWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)



Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.6	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\thetaJA}$	40	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

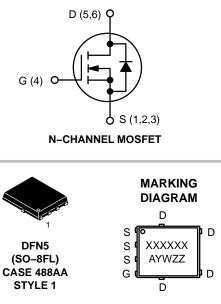
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

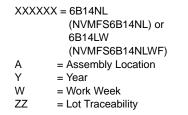


## **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
100 V	13 mΩ @ 10 V	55 A
100 V	19 mΩ @ 4.5 V	35 A





#### ORDERING INFORMATION

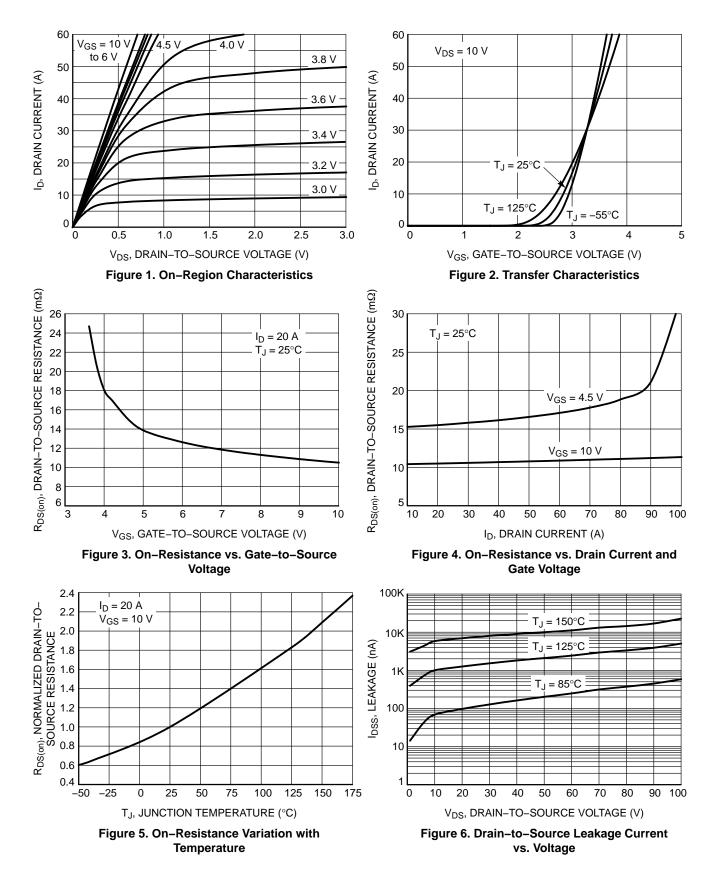
See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

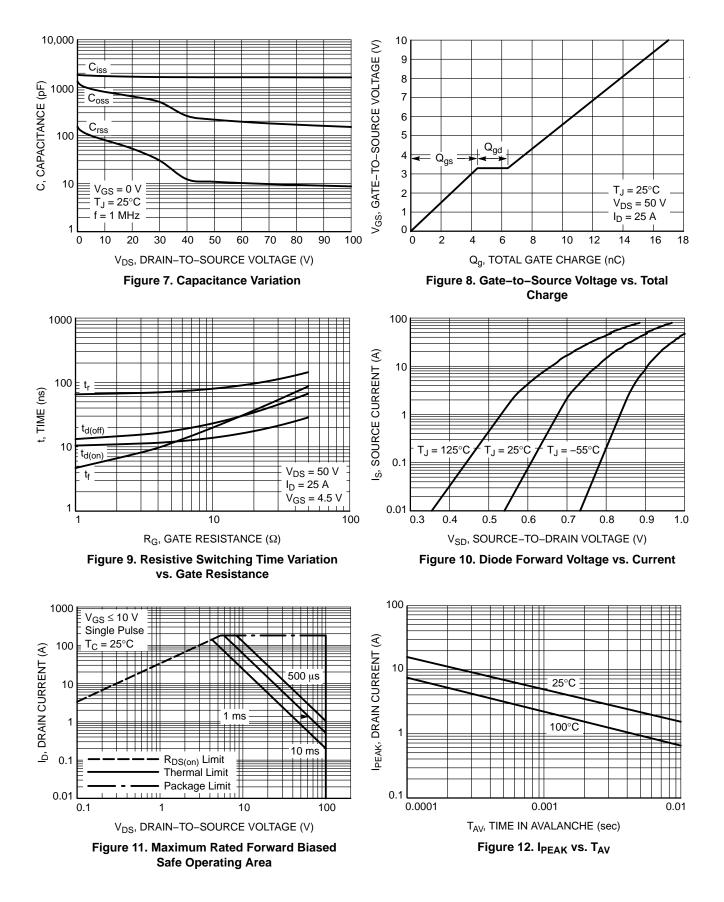
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, I <sub>D</sub> = 250 $\mu$ A		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				80		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	$T_J = 25^{\circ}C$			25	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 16 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \ \mu A$		1.0		3.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.8		mV/°C
	5	$V_{GS} = 10 V$	L 00.4		10.5	13	mΩ
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		15.5	19	
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			1680		pF
Output Capacitance	C <sub>OSS</sub>				580		
Reverse Transfer Capacitance	C <sub>RSS</sub>				42		
Total Gate Charge	-	$V_{GS} = 4.5 \text{ V}, \text{ V}_{DS} = 50 \text{ V}; \text{ I}_{D} = 25 \text{ A}$ $V_{GS} = 10 \text{ V}, \text{ V}_{DS} = 50 \text{ V}; \text{ I}_{D} = 25 \text{ A}$			8		nC
	Q <sub>G(TOT)</sub>				17		
Threshold Gate Charge	Q <sub>G(TH)</sub>				2.2		
Gate-to-Source Charge	Q <sub>GS</sub>				4.1		
Gate-to-Drain Charge	Q <sub>GD</sub>				2.0		
Plateau Voltage	V <sub>GP</sub>				3.3		V
SWITCHING CHARACTERISTICS (Note	5)						
Turn–On Delay Time	t <sub>d(ON)</sub>				11		1
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 50 V, I <sub>D</sub> = 25 A, R <sub>G</sub> = 1.0 $\Omega$			67.6		ns
Turn–Off Delay Time	t <sub>d(OFF)</sub>				14.8		
Fall Time	t <sub>f</sub>				7.2		
DRAIN-SOURCE DIODE CHARACTERI	STICS						
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 V,$ $I_{S} = 20 A$	$T_J = 25^{\circ}C$		0.83	1.2	
			T <sub>J</sub> = 125°C		0.72		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/µs, I <sub>S</sub> = 25 A			48		ns
Charge Time	t <sub>a</sub>				25		
Discharge Time	t <sub>b</sub>				23		
Reverse Recovery Charge	Q <sub>RR</sub>				53		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq 300 \,\mu$ s, duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**



#### **TYPICAL CHARACTERISTICS**



### **TYPICAL CHARACTERISTICS**

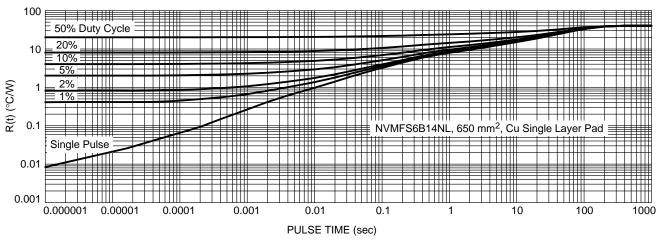


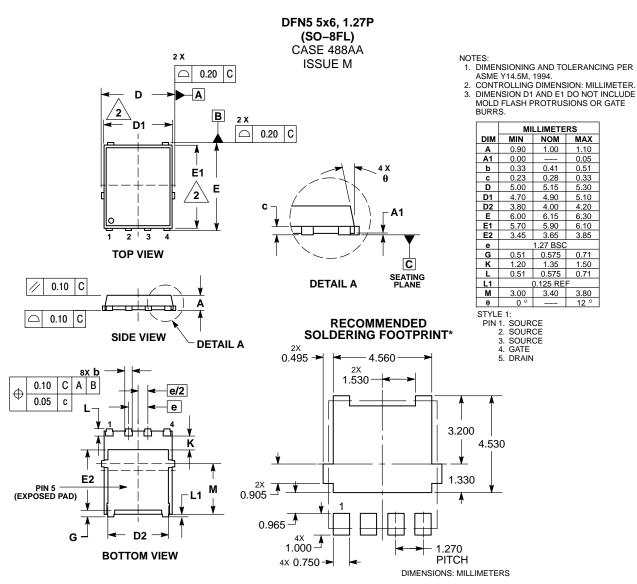
Figure 13. Thermal Response

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS6B14NLT1G	6B14NL	DFN5 (Pb–Free)	1500 / Tape & Reel
NVMFS6B14NLWFT1G	614LLW	DFN5 (Pb–Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS6B14NLT3G	6B14NL	DFN5 (Pb–Free)	5000 / Tape & Reel
NVMFS6B14NLWFT3G	614LLW	DFN5 (Pb–Free, Wettable Flanks)	5000 / Tape & Reel

#### **DEVICE ORDERING INFORMATION**

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT

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